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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	e200z0h
Core Size	32-Bit Single-Core
Speed	64MHz
Connectivity	CANbus, LINbus, SPI, UART/USART
Peripherals	DMA, POR, PWM, WDT
Number of I/O	80
Program Memory Size	1MB (1M x 8)
Program Memory Type	FLASH
EEPROM Size	64K x 8
RAM Size	80K x 8
Voltage - Supply (Vcc/Vdd)	4.5V ~ 5.5V
Data Converters	A/D 26x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	144-LQFP
Supplier Device Package	144-LQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/spc560p60l5cefar

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The crossbar provides the following features:

- 6 master ports:
 - 2 e200z0 core complex Instruction ports
 - 2 e200z0 core complex Load/Store Data ports
 - eDMA
 - FlexRay
- 6 slave ports:
 - 2 Flash memory (code flash and data flash)
 - 2 SRAM (48 KB + 32 KB)
 - 2 PBRIDGE
- 32-bit internal address, 32-bit internal data paths
- Fixed Priority Arbitration based on Port Master
- Temporary dynamic priority elevation of masters

1.5.3

Enhanced direct memory access (eDMA)

The enhanced direct memory access (eDMA) controller is a second-generation module capable of performing complex data movements via 16 programmable channels, with minimal intervention from the host processor. The hardware micro architecture includes a DMA engine which performs source and destination address calculations, and the actual data movement operations, along with an SRAM-based memory containing the transfer control descriptors (TCD) for the channels. This implementation is utilized to minimize the overall block size.

The eDMA module provides the following features:

- 16 channels support independent 8, 16 or 32-bit single value or block transfers
- Supports variable sized queues and circular queues
- Source and destination address registers are independently configured to post-increment or remain constant
- Each transfer is initiated by a peripheral, CPU, or eDMA channel request
- Each eDMA channel can optionally send an interrupt request to the CPU on completion of a single value or block transfer
- DMA transfers possible between system memories, DSPIs, ADC, eTimer and CTU
- Programmable DMA Channel Multiplexer for assignment of any DMA source to any available DMA channel with up to 30 potential request sources
- eDMA abort operation through software

1.5.4

On-chip flash memory with ECC

The SPC56xP54x/SPC56xP60x provides up to 1024 KB of programmable, non-volatile, flash memory. The non-volatile memory (NVM) can be used for instruction and/or data storage. The flash memory module interfaces the system bus to a dedicated flash memory array controller. It supports a 32-bit data bus width at the system bus port, and a 128-bit read data interface to flash memory. The module contains a four-entry, 4x128-bit prefetch buffers. Prefetch buffer hits allow no-wait responses. Normal flash memory array accesses are registered and are forwarded to the system bus on the following cycle, incurring 2 wait states.

The default booting scheme is the one which uses the internal flash memory (an internal pull-down is used to select this mode). The alternate option allows the user to boot via FlexCAN or LINFlex (using the boot assist module software).

A censorship scheme is provided to protect the contents of the flash memory and offer increased security for the entire device.

A password mechanism is designed to grant the legitimate user access to the non-volatile memory.

1.5.16.1 Boot assist module (BAM)

The BAM is a block of read-only one-time programmed memory and is identical for all SPC56xP54x/SPC56xP60x devices that are based on the e200z0h core. The BAM program is executed every time the device is powered on if the alternate boot mode has been selected by the user.

The BAM provides the following features:

- Serial bootloading via FlexCAN or LINFlex.
- BAM can accept a password via the used serial communication channel to grant the legitimate user access to the non-volatile memory.

1.5.17 Error correction status module (ECSM)

The ECSM on this device features the following:

- Platform configuration and revision
- ECC error reporting for flash memory and SRAM
- ECC error injection for SRAM

The ECSM module is replicated for each processor.

1.5.18 FlexCAN

The FlexCAN module is a communication controller implementing the CAN protocol according to Bosch Specification version 2.0B. The CAN protocol was designed to be used primarily as a vehicle serial data bus, meeting the specific requirements of this field: real-time processing, reliable operation in the EMI environment of a vehicle, cost-effectiveness and required bandwidth. FlexCAN module contains 32 message buffers.

The FlexCAN module provides the following features:

- Full implementation of the CAN protocol specification, Version 2.0B
 - Standard data and remote frames
 - Extended data and remote frames
 - 0 to 8 bytes data length
 - Programmable bit rate as fast as 1 Mbit/s
- 32 message buffers of 0 to 8 bytes data length
- Each message buffer configurable as Rx or Tx, all supporting standard and extended messages
- Programmable loop-back mode supporting self-test operation
- 3 programmable mask registers

Table 5. Supply pins (continued)

Supply		Pin		
Symbol	Description	LQFP 100	LQFP 144	LQFP 176 ⁽¹⁾
V _{DD_HV_REG} (3.3 V or 5.0 V)	Voltage regulator supply voltage	50	72	86
V _{DD_LV_REGCOR}	1.2 V decoupling ⁽²⁾ pins for core logic supply and voltage regulator feedback. Decoupling capacitor must be connected between this pins and V _{SS_LV_REGCOR} .	48	70	82
V _{SS_LV_REGCOR}	1.2 V decoupling ⁽²⁾ pins for core logic GND and voltage regulator feedback. Decoupling capacitor must be connected between this pins and V _{DD_LV_REGCOR} .	49	71	85
ADC0 reference and supply voltage				
V _{DD_HV_AD}	ADC supply and high reference voltage	39	56	64
V _{SS_HV_AD}	ADC ground and low reference voltage	40	57	65
Power supply pins (3.3 V or 5.0 V)				
V _{DD_HV_IO0}	Input/Output supply voltage	—	6	14
V _{SS_HV_IO0}	Input/Output ground	—	7	15
V _{DD_HV_IO1}	Input/Output supply voltage	13	21	29
V _{SS_HV_IO1}	Input/Output ground	14	22	30
V _{DD_HV_IO2}	Input/Output supply voltage	63	91	115
V _{SS_HV_IO2}	Input/Output ground	62	90	114
V _{DD_HV_IO3}	Input/Output supply voltage	87	126	150
V _{SS_HV_IO3}	Input/Output ground	88	127	151
V _{DD_HV_IO4}	Input/Output supply voltage	—	—	169
V _{SS_HV_IO4}	Input/Output ground	—	—	170
V _{DD_HV_IO5}	Input/Output supply voltage	—	—	5
V _{SS_HV_IO5}	Input/Output ground	—	—	6
V _{DD_HV_IO6}	Input/Output supply voltage	—	—	108
V _{SS_HV_IO6}	Input/Output ground	—	—	109
V _{DD_HV_FL}	Code and data flash supply voltage	69	97	121
V _{SS_HV_FL}	Code and data flash supply ground	68	96	120
V _{DD_HV_OSC}	Crystal oscillator amplifier supply voltage	16	27	35
V _{SS_HV_OSC}	Crystal oscillator amplifier ground	17	28	36
Power supply pins (1.2 V)				
V _{DD_LV_COR0}	1.2 V Decoupling pins for core logic supply. Decoupling capacitor must be connected between these pins and the nearest V _{SS_LV_COR0} pin.	12	18	26

Table 7. Pin muxing⁽¹⁾ (continued)

Port pin	PCR No.	Alternate function ⁽²⁾ , (3)	Functions	Peripheral ⁽⁴⁾	I/O direction ⁽⁵⁾	Pad speed ⁽⁶⁾		Pin		
						SRC = 0	SRC = 1	LQFP 100	LQFP 144	LQFP 176 ⁽⁷⁾
B[9]	PCR[25]	ALT0 — ALT1 — ALT2 — ALT3 —	GPIO[25] — — — — AN[11]	SIUL — — — — ADC_0	Input Only	—	—	35	52	60
B[10]	PCR[26]	ALT0 — ALT1 — ALT2 — ALT3 —	GPIO[26] — — — — AN[12]	SIUL — — — — ADC_0	Input Only	—	—	36	53	61
B[11]	PCR[27]	ALT0 — ALT1 — ALT2 — ALT3 —	GPIO[27] — — — — AN[13]	SIUL — — — — ADC_0	Input Only	—	—	37	54	62
B[12]	PCR[28]	ALT0 — ALT1 — ALT2 — ALT3 —	GPIO[28] — — — — AN[14]	SIUL — — — — ADC_0	Input Only	—	—	38	55	63
B[13]	PCR[29]	ALT0 — ALT1 — ALT2 — ALT3 — —	GPIO[29] — — — — AN[16] RXD	SIUL — — — — ADC_0 LINFlex_1	Input Only	—	—	42	60	68
B[14]	PCR[30]	ALT0 — ALT1 — ALT2 — ALT3 — —	GPIO[30] — — — — AN[17] ETC[4] EIRQ[19]	SIUL — — — — ADC_0 eTimer_0 SIUL	Input Only	—	—	44	64	76
B[15]	PCR[31]	ALT0 — ALT1 — ALT2 — ALT3 — —	GPIO[31] — — — — AN[18] EIRQ[20]	SIUL — — — — ADC_0 SIUL	Input Only	—	—	43	62	70

Table 7. Pin muxing⁽¹⁾ (continued)

Port pin	PCR No.	Alternate function ⁽²⁾ , (3)	Functions	Peripheral ⁽⁴⁾	I/O direction ⁽⁵⁾	Pad speed ⁽⁶⁾		Pin		
						SRC = 0	SRC = 1	LQFP 100	LQFP 144	LQFP 176 ⁽⁷⁾
C[15]	PCR[47]	ALT0 ALT1 ALT2 ALT3 —	GPIO[47] CA_TR_EN ETC[0] — EXT_IN	SIUL FlexRay_0 eTimer_1 — CTU_0	I/O O I/O — I	Slow	Symmetric	85	124	148
Port D										
D[0]	PCR[48]	ALT0 ALT1 ALT2 ALT3	GPIO[48] CA_TX ETC[1] —	SIUL FlexRay_0 eTimer_1 —	I/O O I/O —	Slow	Symmetric	86	125	149
D[1]	PCR[49]	ALT0 ALT1 ALT2 ALT3 —	GPIO[49] CS4_1 ETC[2] EXT_TRG CA_RX	SIUL DSPI_1 eTimer_1 CTU_0 FlexRay_0	I/O O I/O O I	Slow	Medium	3	3	3
D[2]	PCR[50]	ALT0 ALT1 ALT2 ALT3 —	GPIO[50] CS5_1 ETC[3] — CB_RX	SIUL DSPI_1 eTimer_1 — FlexRay_0	I/O O I/O — I	Slow	Medium	97	140	168
D[3]	PCR[51]	ALT0 ALT1 ALT2 ALT3	GPIO[51] CB_TX ETC[4] —	SIUL FlexRay_0 eTimer_1 —	I/O O I/O —	Slow	Symmetric	89	128	152
D[4]	PCR[52]	ALT0 ALT1 ALT2 ALT3	GPIO[52] CB_TR_EN ETC[5] —	SIUL FlexRay_0 eTimer_1 —	I/O O I/O —	Slow	Symmetric	90	129	153
D[5]	PCR[53]	ALT0 ALT1 ALT2 ALT3	GPIO[53] CS3_0 — SOUT_3	SIUL DSPI_0 — DSPI_3	I/O O — O	Slow	Medium	22	33	41
D[6]	PCR[54]	ALT0 ALT1 ALT2 ALT3	GPIO[54] CS2_0 SCK_3 SOUT_4	SIUL DSPI_0 DSPI_3 DSPI_4	I/O O I/O O	Slow	Medium	23	34	42

Table 7. Pin muxing⁽¹⁾ (continued)

Port pin	PCR No.	Alternate function ^{(2), (3)}	Functions	Peripheral ⁽⁴⁾	I/O direction ⁽⁵⁾	Pad speed ⁽⁶⁾		Pin		
						SRC = 0	SRC = 1	LQFP 100	LQFP 144	LQFP 176 ⁽⁷⁾
E[15]	PCR[79]	ALT0	GPIO[79]	SIUL	I/O	Slow	Medium	—	121	145
		ALT1	—	—	—					
		ALT2	—	—	—					
		ALT3	—	—	—	Slow	Medium	—	121	145
		—	SIN_3	DSPI_3						
		—	EIRQ[27]	SIUL						
Port F										
F[0]	PCR[80]	ALT0	GPIO[80]	SIUL	I/O	Slow	Medium	—	133	157
		ALT1	DBG_0	FlexRay_0	O					
		ALT2	CS3_3	DSPI_3	O					
F[1]	PCR[81]	ALT3	—	—	—	Slow	Medium	—	135	159
		—	EIRQ[28]	SIUL						
		ALT0	GPIO[81]	SIUL	I/O					
F[2]	PCR[82]	ALT1	DBG_1	FlexRay_0	O	Slow	Medium	—	137	161
		ALT2	CS2_3	DSPI_3	O					
		ALT3	—	—	—					
F[3]	PCR[83]	—	EIRQ[29]	SIUL		Slow	Medium	—	139	167
		ALT0	GPIO[82]	SIUL	I/O					
		ALT1	DBG_2	FlexRay_0	O					
F[4]	PCR[84]	ALT2	CS1_3	DSPI_3	O	Slow	Medium	—	137	161
		ALT3	—	—	—					
		—	MDO[3]	nexus_0						
F[5]	PCR[85]	ALT0	—	—	—	Slow	Fast	—	4	4
		ALT1	—	—	—					
		ALT2	MDO[2]	nexus_0	O					
F[6]	PCR[86]	ALT3	—	—	—	Slow	Fast	—	5	13
		ALT0	GPIO[86]	SIUL	I/O					
		ALT1	—	—	O					
F[7]	PCR[87]	ALT2	MDO[1]	nexus_0	O	Slow	Fast	—	8	16
		ALT3	—	—	—					

3 Electrical characteristics

3.1 Introduction

This section contains electrical characteristics of the device as well as temperature and power considerations.

This product contains devices to protect the inputs against damage due to high static voltages. However, it is advisable to take precautions to avoid application of any voltage higher than the specified maximum rated voltages.

To enhance reliability, unused inputs can be driven to an appropriate logic voltage level (V_{DD} or V_{SS}). This can be done by the internal pull-up or pull-down, which is provided by the product for most general purpose pins.

The parameters listed in the following tables represent the characteristics of the device and its demands on the system.

In the tables where the device logic provides signals with their respective timing characteristics, the symbol "CC" for Controller Characteristics is included in the Symbol column.

In the tables where the external system must provide signals with their respective timing characteristics to the device, the symbol "SR" for System Requirement is included in the Symbol column.

Caution: All of the following parameter values can vary depending on the application and must be confirmed during silicon validation, silicon characterization or silicon reliability trial.

3.2 Parameter classification

The electrical parameters shown in this supplement are guaranteed by various methods. To give the customer a better understanding, the classifications listed in [Table 8](#) are used and the parameters are tagged accordingly in the tables where appropriate.

Table 8. Parameter classifications

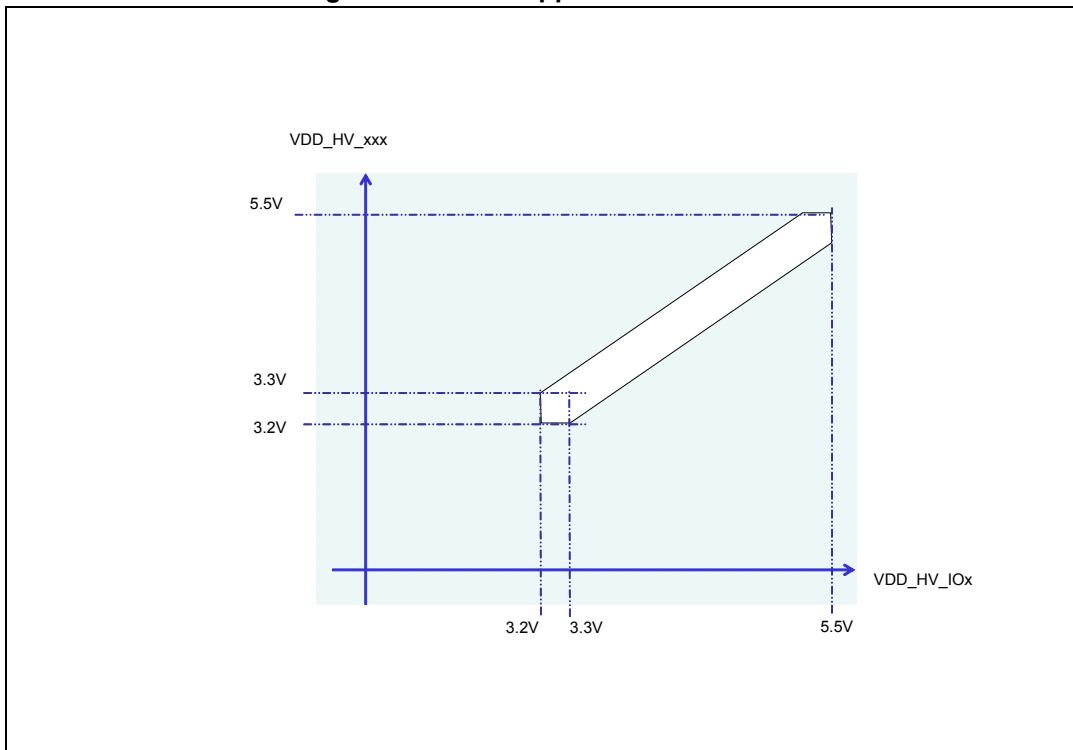
Classification tag	Tag description
P	Those parameters are guaranteed during production testing on each individual device.
C	Those parameters are achieved by the design characterization by measuring a statistically relevant sample size across process variations.
T	Those parameters are achieved by design characterization on a small sample size from typical devices under typical conditions unless otherwise noted. All values shown in the typical column are within this category.
D	Those parameters are derived mainly from simulations.

Note: *The classification is shown in the column labeled "C" in the parameter tables where appropriate.*

3.3 Absolute maximum ratings

Table 9. Absolute maximum ratings⁽¹⁾

Symbol		Parameter	Conditions	Min	Max ⁽²⁾	Unit
V_{SS_HV}	SR	Digital ground	—	0	0	V
$V_{DD_HV_IOx}^{(3)}$	SR	3.3 V / 5.0 V input/output supply voltage with respect to ground (V_{SS_HV})	—	-0.3	6.0	V
$V_{SS_HV_IOx}$	SR	Input/output ground voltage with respect to ground (V_{SS_HV})	—	-0.1	0.1	V
$V_{DD_HV_FL}$	SR	3.3 V / 5.0 V code and data flash memory supply voltage with respect to ground (V_{SS_HV})	—	-0.3	6.0	V
			Relative to $V_{DD_HV_IOx}$	-0.3	$V_{DD_HV_IOx} + 0.3$	
$V_{SS_HV_FL}$	SR	Code and data flash memory ground with respect to ground (V_{SS_HV})	—	-0.1	0.1	V
$V_{DD_HV_OSC}$	SR	3.3 V / 5.0 V crystal oscillator amplifier supply voltage with respect to ground (V_{SS_HV})	—	-0.3	6.0	V
			Relative to $V_{DD_HV_IOx}$	-0.3	$V_{DD_HV_IOx} + 0.3$	
$V_{SS_HV_OSC}$	SR	3.3 V / 5.0 V crystal oscillator amplifier reference voltage with respect to ground (V_{SS_HV})	—	-0.1	0.1	V
$V_{DD_HV_REG}$	SR	3.3 V / 5.0 V voltage regulator supply voltage with respect to ground (V_{SS_HV})	—	-0.3	6.0	V
			Relative to $V_{DD_HV_IOx}$	-0.3	$V_{DD_HV_IOx} + 0.3$	
$V_{DD_HV_AD}$	SR	3.3 V / 5.0 V ADC supply and high reference voltage with respect to ground (V_{SS_HV})	$V_{DD_HV_REG} < 2.7\text{ V}$	-0.3	$V_{DD_HV_REG} + 0.3$	V
			$V_{DD_HV_REG} > 2.7\text{ V}$	-0.3	6.0	
$V_{SS_HV_AD}$	SR	ADC ground and low reference voltage with respect to ground (V_{SS_HV})	—	-0.1	0.1	V
T_{VDD}	SR	Slope characteristics on all V_{DD} during power up ⁽⁴⁾ with respect to ground (V_{SS_HV})	—	3.0 ⁽⁵⁾	500×10^3 (0.5 [V/ μ s])	V/s
V_{IN}	SR	Voltage on any pin with respect to ground ($V_{SS_HV_IOx}$) with respect to ground (V_{SS_HV})	—	-0.3	6.0	V
			Relative to $V_{DD_HV_IOx}$	-0.3	$V_{DD_HV_IOx} + 0.3$	
V_{INAN}	SR	Analog input voltage	$V_{DD_HV_REG} < 2.7\text{ V}$	$V_{SS_HV_AD} - 0.3$	$V_{DD_HV_AD} + 0.3$	V
			$V_{DD_HV_REG} > 2.7\text{ V}$	$V_{SS_HV_AD}$	$V_{DD_HV_AD}$	
I_{INJPAD}	SR	Injected input current on any pin during overload condition	—	-10	10	mA

Figure 7. Power supplies constraints^(f)

The SPC56xP54x/SPC56xP60x supply architecture provides an ADC supply that is managed independently of standard V_{DD_HV} supply. [Figure 8](#) shows the constraints of the ADC power supply.

f. IO AC and DC characteristics are guaranteed only in the range 3.0 V–3.6 V when PAD3V5V is low, and in the range 4.5 V–5.5 V when PAD3V5V is high.

$R_{\theta JC}$ is device related and cannot be influenced by the user. The user controls the thermal environment to change the case to ambient thermal resistance, $R_{\theta CA}$. For instance, the user can change the size of the heat sink, the air flow around the device, the interface material, the mounting arrangement on printed circuit board, or change the thermal dissipation on the printed circuit board surrounding the device.

To determine the junction temperature of the device in the application when heat sinks are not used, the Thermal Characterization Parameter (Ψ_{JT}) can be used to determine the junction temperature with a measurement of the temperature at the top center of the package case using [Equation 3](#):

$$\text{Equation 3 } T_J = T_T + (\Psi_{JT} \times P_D)$$

where:

T_T = thermocouple temperature on top of the package (°C)

Ψ_{JT} = thermal characterization parameter (°C/W)

P_D = power dissipation in the package (W)

The thermal characterization parameter is measured per JESD51-2 specification using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over about 1 mm of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by cooling effects of the thermocouple wire.

3.5.1.1 References

Semiconductor Equipment and Materials International
3081 Zanker Road
San Jose, CA 95134 U.S.A.
(408) 943-6900

MIL-SPEC and EIA/JESD (JEDEC) specifications are available from Global Engineering Documents at 800-854-7179 or 303-397-7956.

JEDEC specifications are available on the WEB at jedec.org web site.

1. C.E. Triplett and B. Joiner, *An Experimental Characterization of a 272 PBGA Within an Automotive Engine Controller Module*, Proceedings of SemiTherm, San Diego, 1998, pp. 47-54.
2. G. Kromann, S. Shidore, and S. Addison, *Thermal Modeling of a PBGA for Air-Cooled Applications*, Electronic Packaging and Production, pp. 53-58, March 1998.
3. B. Joiner and V. Adams, *Measurement and Simulation of Junction to Board Thermal Resistance and Its Application in Thermal Modeling*, Proceedings of SemiTherm, San Diego, 1999, pp. 212-220.

Table 17. Voltage regulator electrical characteristics

Symbol	C	Parameter	Conditions	Value			Unit
				Min	Typ	Max	
V _{DD_LV_REGCOR}	CC	P	Output voltage under maximum load run supply current configuration	Post-trimming	1.15	—	1.32 V
C _{DEC1}	SR	—	External decoupling/stability ceramic capacitor	BJT from Table 16 . 3 capacitances (i.e. X7R or X8R capacitors) with nominal value of 10 µF	19.5	30	— µF
				BJT BC817, one capacitance of 22 µF	14.3	22	— µF
R _{REG}	SR	—	Resulting ESR of all three capacitors of C _{DEC1}	BJT from Table 16 . 3x10 µF. Absolute maximum value between 100 kHz and 10 MHz	—	—	50 mΩ
			Resulting ESR of the unique capacitor C _{DEC1}	BJT BC817, 1x 22 µF. Absolute maximum value between 100 kHz and 10 MHz	10	—	40 mΩ
C _{DEC2}	SR	—	External decoupling/stability ceramic capacitor	4 capacitances (i.e. X7R or X8R capacitors) with nominal value of 440 nF	1200	1760	— nF
C _{DEC3}	SR	—	External decoupling/stability ceramic capacitor on V _{DD_HV_REG}	3 capacitances (i.e. X7R or X8R capacitors) with nominal value of 10 µF; C _{DEC3} has to be equal or greater than C _{DEC1}	19.5	30	— µF
L _{Reg}	SR	—	Resulting ESL of V _{DD_HV_REG} , BCTRL and V _{DD_LV_CORx} pins	—	—	—	15 nH

3.8.2 Voltage monitor electrical characteristics

The device implements a Power On Reset module to ensure correct power-up initialization, as well as three low voltage detectors to monitor the V_{DD} and the V_{DD_LV} voltage while device is supplied:

- POR monitors V_{DD} during the power-up phase to ensure device is maintained in a safe reset state
- LVDHV3 monitors V_{DD} to ensure device reset below minimum functional supply
- LVDHV5 monitors V_{DD} when application uses device in the 5.0V ± 10% range
- LVDLVCOR monitors low voltage digital power domain

Figure 10. Power-up typical sequence

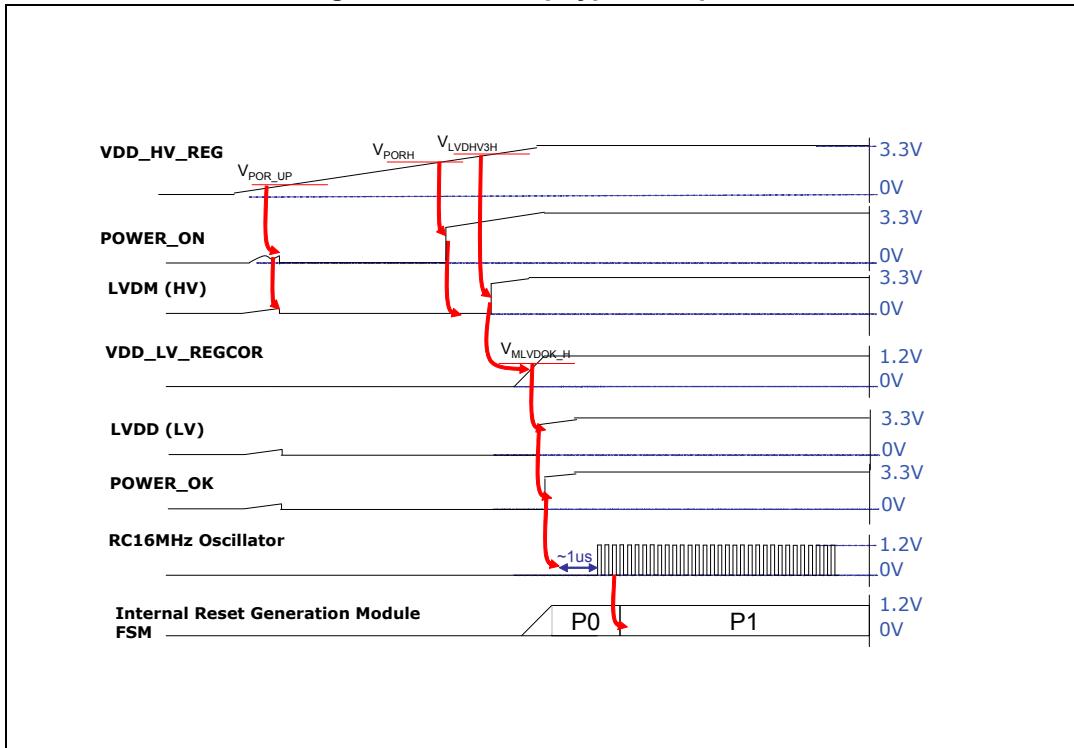


Figure 11. Power-down typical sequence

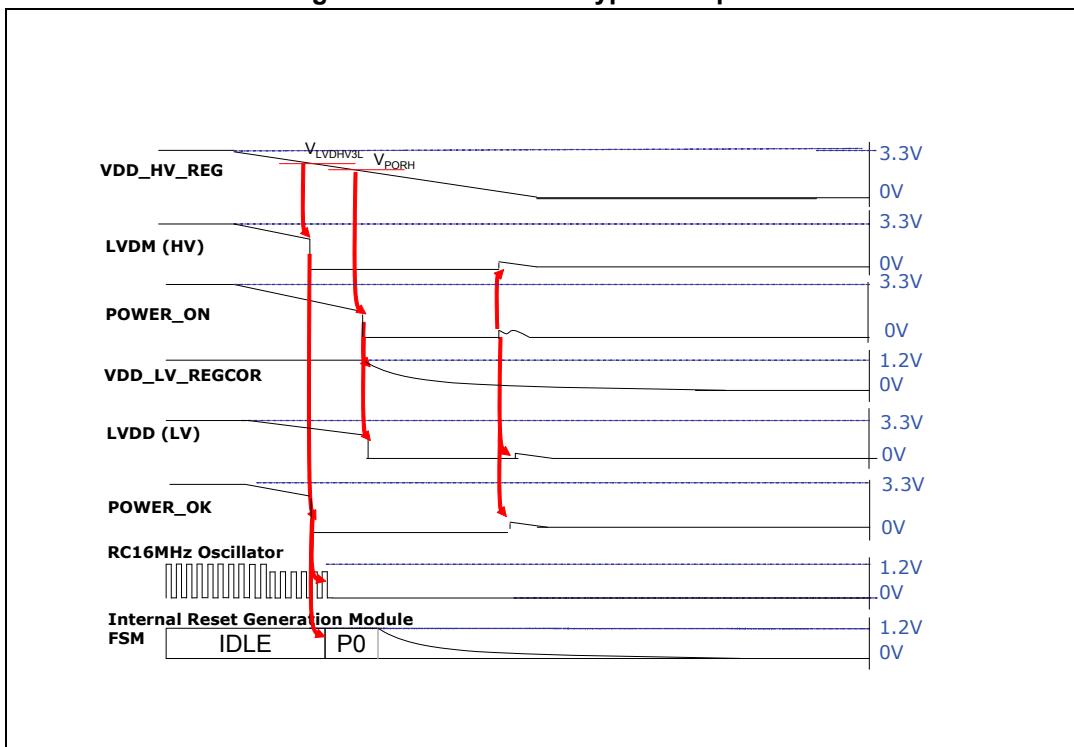
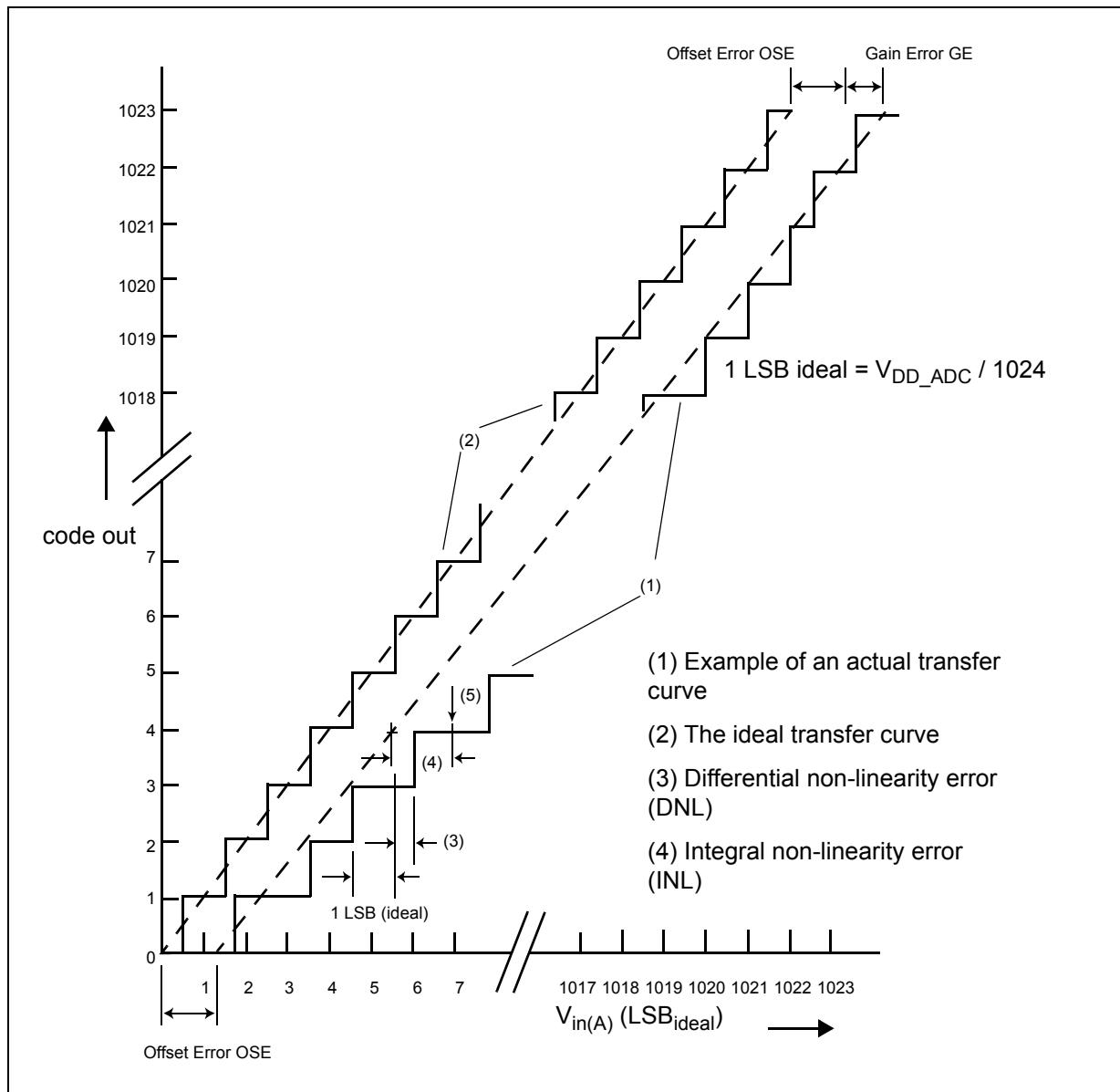


Figure 15. ADC characteristics and error definitions



3.15.1 Input impedance and ADC accuracy

To preserve the accuracy of the A/D converter, it is necessary that analog input pins have low AC impedance. Placing a capacitor with good high-frequency characteristics at the input pin of the device can be effective: the capacitor should be as large as possible, ideally infinite. This capacitor contributes to attenuate the noise present on the input pin; further, it sources charge during the sampling phase, when the analog signal source is a high-impedance source.

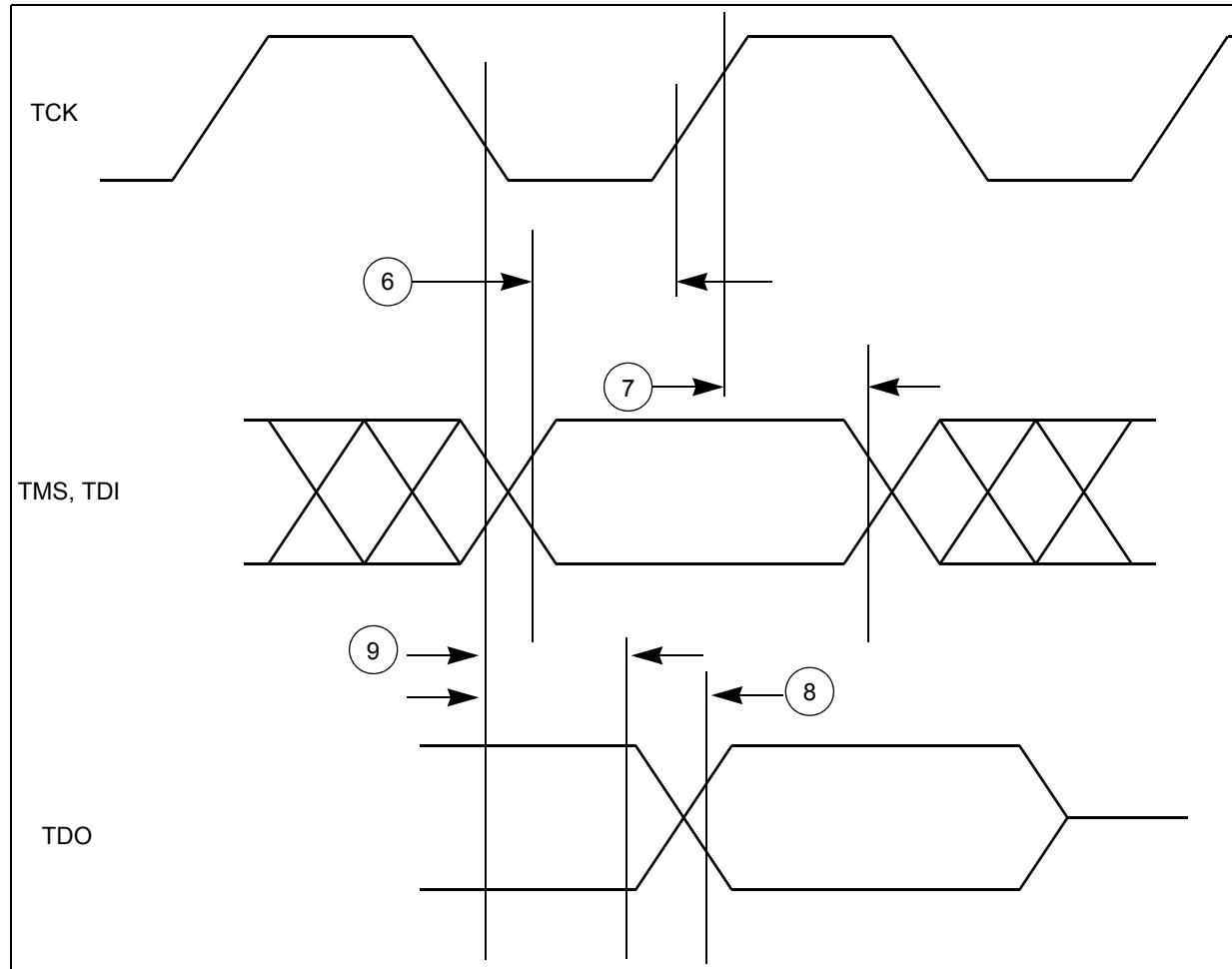
A real filter can typically be obtained by using a series resistance with a capacitor on the input pin (simple RC filter). The RC filtering may be limited according to the source impedance value of the transducer or circuit supplying the analog signal to be measured.

3.15.2 ADC conversion characteristics

Table 32. ADC conversion characteristics

Symbol		Parameter	Conditions ⁽¹⁾	Value			Unit
				Min	Typ	Max	
V _{INAN}	SR	Analog input voltage ⁽²⁾	—	V _{SS_HV_AD} —0.3	—	V _{SS_HV_AD} +0.3	V
f _{CK}	SR	ADC Clock frequency (depends on ADC configuration) (The duty cycle depends on AD_clk ⁽³⁾ frequency)	—	3 ⁽⁴⁾	—	60	MHz
f _s	SR	Sampling frequency	—	—	—	1.53	MHz
t _{ADC_S}	D	Sample time ⁽⁵⁾	f _{ADC} = 20 MHz, INPSAMP = 3	125	—	—	ns
			f _{ADC} = 9 MHz, INPSAMP = 255	—	—	28.2	μs
t _{ADC_C}	P	Conversion time ⁽⁶⁾	f _{ADC} = 20 MHz ⁽⁷⁾ , INPCMP = 1	0.650	—	—	μs
C _S ⁽⁸⁾	D	ADC input sampling capacitance	—	—	—	2.5	pF
C _{P1} ⁽⁸⁾	D	ADC input pin capacitance 1	—	—	—	3	pF
C _{P2} ⁽⁸⁾	D	ADC input pin capacitance 2	—	—	—	1	pF
C _{P3} ⁽⁸⁾	D	ADC input pin capacitance 3	—	—	—	1	pF
R _{SW1} ⁽⁸⁾	D	Internal resistance of analog source	V _{DD_HV_AD} = 5 V ±10%	—	—	0.6	kΩ
			V _{DD_HV_AD} = 3.3 V ±10%	—	—	3	kΩ
R _{SW2} ⁽⁸⁾	D	Internal resistance of analog source	V _{DD_HV_AD} = 5 V ±10%	—	—	2.15	kΩ
			V _{DD_HV_AD} = 3.3 V ±10%	—	—	3.6	kΩ
R _{AD} ⁽⁸⁾	D	Internal resistance of analog source	—	—	—	2	kΩ
I _{INJ}	T	Input current injection	Current injection on one ADC input, different from the converted one. Remains within TUE spec.	-5	—	5	mA
INL	P	Integral Non Linearity	No overload	—	±1.5	—	LSB
DNL	P	Differential Non Linearity	No overload	-1.0	—	1.0	LSB
OFS	T	Offset error	—	—	±1	—	LSB
GNE	T	Gain error	—	—	±1	—	LSB
TUE	P	Total unadjusted error without current injection	16 precision channels	-2.5	—	2.5	LSB

Figure 27. Nexus TDI, TMS, TDO timing



3.18.4 External interrupt timing (IRQ pin)

Table 40. External interrupt timing⁽¹⁾

No.	Symbol	C	Parameter	Conditions	Min	Max	Unit	
1	t_{IPWL}	CC	D	IRQ pulse width low	—	4	—	t_{CYC}
2	t_{IPWH}	CC	D	IRQ pulse width high	—	4	—	t_{CYC}
3	t_{ICYC}	CC	D	IRQ edge to edge time ⁽²⁾	—	$4 + N^{(3)}$	—	t_{CYC}

1. IRQ timing specified at $f_{SYS} = 64$ MHz and $V_{DD_HV_IOx} = 3.0$ V to 5.5 V, $T_A = T_L$ to T_H , and $CL = 200\text{pF}$ with SRC = 0b00.

2. Applies when IRQ pins are configured for rising edge or falling edge events, but not both.

3. N= ISR time to clear the flag.

Table 42. LQFP144 mechanical data

Symbol	mm			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
A	—	—	1.600	—	—	0.0630
A1	0.050	—	0.150	0.0020	—	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	—	0.200	0.0035	—	0.0079
D	21.800	22.000	22.200	0.8583	0.8661	0.8740
D1	19.800	20.000	20.200	0.7795	0.7874	0.7953
D3	—	17.500	—	—	0.6890	—
E	21.800	22.000	22.200	0.8583	0.8661	0.8740
E1	19.800	20.000	20.200	0.7795	0.7874	0.7953
E3	—	17.500	—	—	0.6890	—
e	—	0.500	—	—	0.0197	—
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	—	1.000	—	—	0.0394	—
k	0.0 °	3.5 °	7.0°	3.5 °	0.0 °	7.0 °
ccc ⁽²⁾	0.080			0.0031		

1. Values in inches are converted from mm and rounded to 4 decimal digits.

2. Tolerance.

4.2.2 LQFP100 mechanical outline drawing

Figure 39. LQFP100 package mechanical drawing

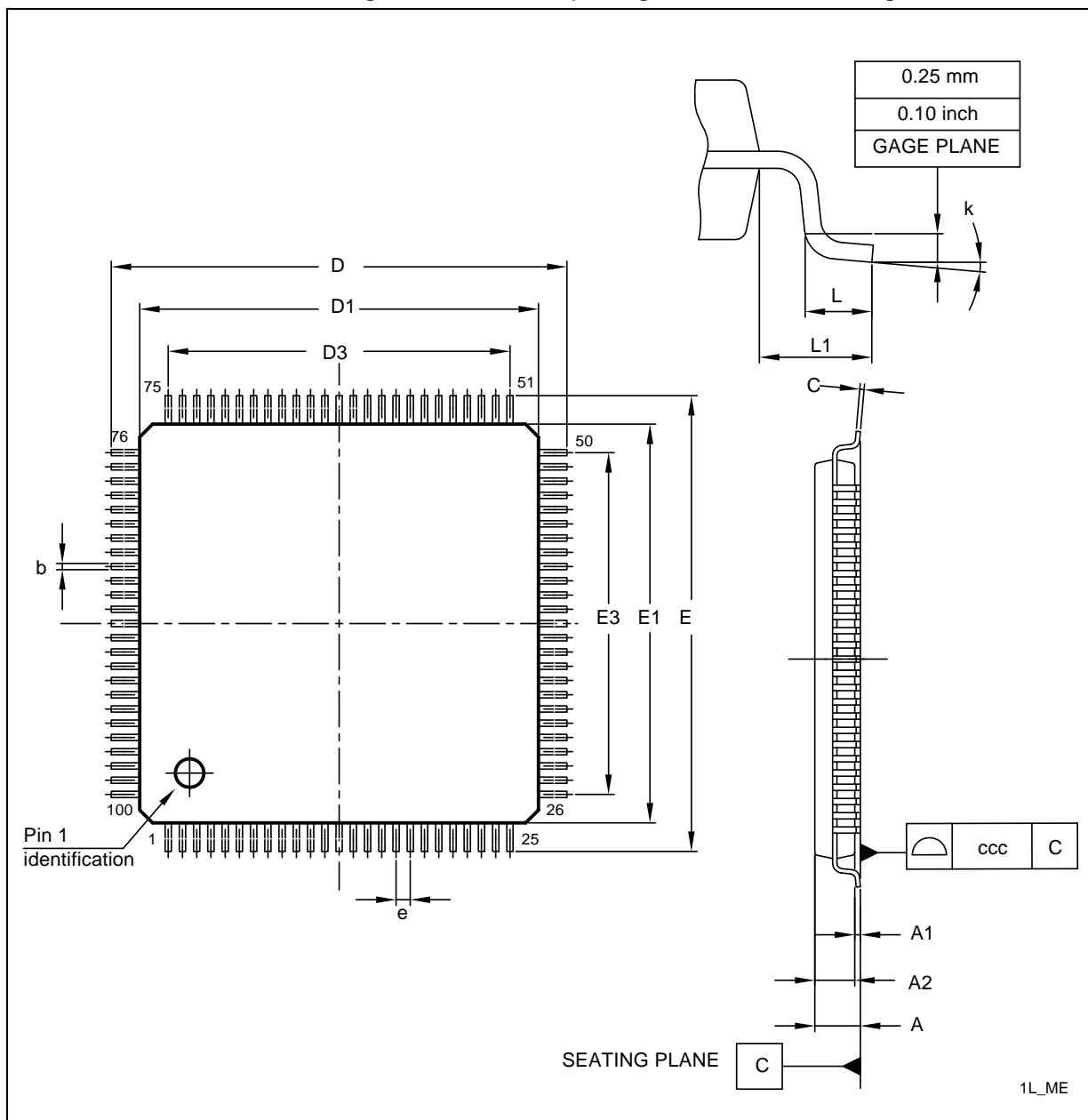


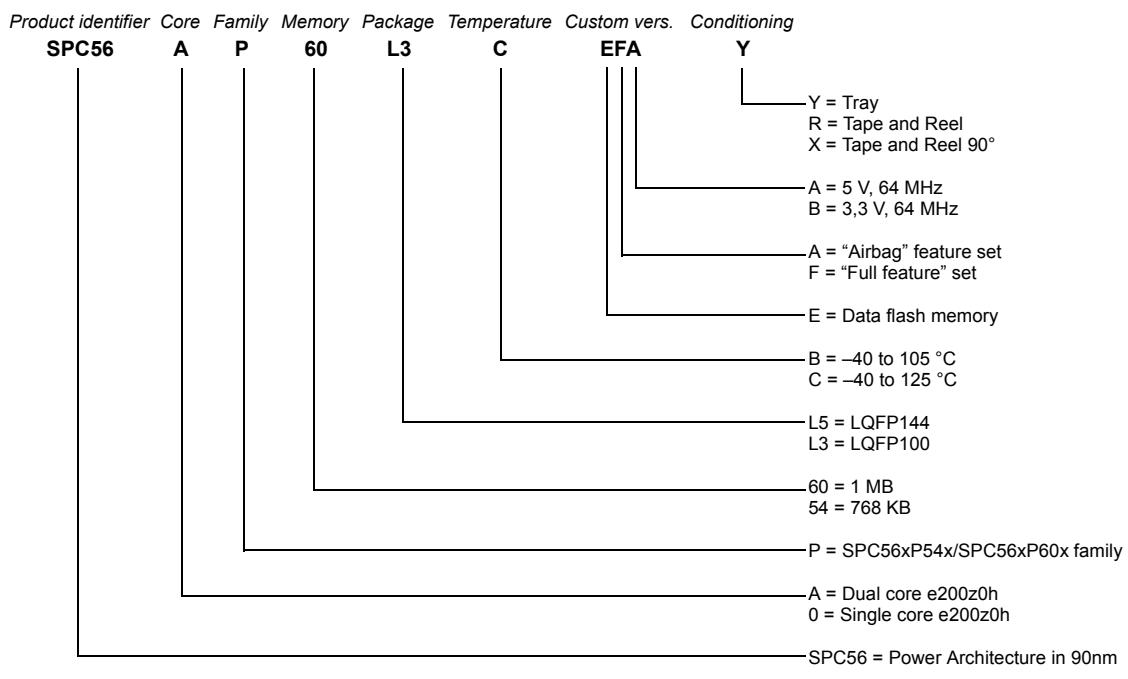
Table 43. LQFP100 mechanical data

Symbol	mm			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
A	—	—	1.600	—	—	0.0630
A1	0.050	—	0.150	0.0020	—	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571

5 Ordering information

Figure 40. Ordering information scheme^(h)

Example code:



h. Not all configurations are available on the market. Please contact your ST sales representative to get the list of orderable commercial part number.

Table 44. Document revision history (continued)

Date	Revision	Substantive changes
21-Nov-2012	4	<p>In the cover page, replaced “64 MHz, dual issue, 32-bit CPU core complex” with “64 MHz, single issue, 32-bit CPU core complex”</p> <p><i>Table 9: Absolute maximum ratings</i>, updated $T_{V_{DD}}$ entry</p> <p><i>Table 22: DC electrical characteristics (3.3 V, NVUSRO[PAD3V5V]=1)</i>:</p> <ul style="list-style-type: none"> Updated conditions value of V_{OL_F} to 11 mA Updated conditions value of V_{OH_F} to –11 mA <p><i>Table 24: Peripherals supply current (5 V and 3.3 V)</i>:</p> <ul style="list-style-type: none"> Replaced all occurrences of I_{DD_BV} in this table with I_{DD_HV} Replaced all occurrences of VDD_BV in this table with VDD_HV_REG. <p><i>Figure 40: Ordering information scheme</i>, fixed typo in the footnote.</p>
18-Sep-2013	5	Updated Disclaimer.
15-Jun-2016	6	<p>Added “AEC-Q10x qualified” in <i>Features</i> section.</p> <p>In <i>Table 2: SPC56xP54x/SPC56xP60x device comparison</i> added footnote “LinFlex_1 is Master Only.” related to row “LINFlex modules”</p> <p>Updated <i>Table 3: SPC56xP54x/SPC56xP60x device configuration difference</i></p> <p><i>Figure 2: LQFP176 pinout (top view)</i>:</p> <ul style="list-style-type: none"> – Changed PB[4] to TDO – Changed PB[5] to TDI – Changed pins 71,72 to NC – Changed pins 87,88 to NC <p>In <i>Section 1.5.27: Nexus development interface (NDI)</i>, added note “At least one TCK clock is necessary for the EVTI signal to be recognized by the MCU.” for EVTI pin.</p> <p>In <i>Table 7: Pin muxing</i>:</p> <ul style="list-style-type: none"> – Replaced “PCR register” with “PCR No.” – Updated “CS3” with “CS3_4” function related to A[2] port pin – In column “I/O direction”, added “O” for “DSPI_1” peripheral – In “Functions” column related to D[12] port pin, changed DS7_1 to CS7_1